What is claimed is:

1. A sense amplifier driver which outputs an enable signal for enabling a sense amplifier, the sense amplifier driver comprising:

a first inverter which receives an input signal and outputs an output signal swung between a ground voltage and a control voltage which is determined by the amount of an off-current flowing through at least one transistor in an inactive memory block; and

a second inverter which receives the output signal of the first inverter and delays and buffers the output signal of the first inverter by a period of time inversely proportional to a level of the control voltage.

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- 2. The sense amplifier driver of claim 1, wherein a point in time when the enable signal is activated is varied according to the level of the control voltage.
- 3. A sense amplifier driver comprising a first inverter and a second inverter, wherein the first inverter comprises:

a first pull-up transistor having a gate for receiving an input signal, a first electrode for receiving a control voltage inversely proportional to the amount of an off-current flowing through at least one transistor in an inactive memory block, and a second electrode connected to an output terminal of the first inverter; and

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a first pull-down transistor having a gate for receiving the input signal, a first electrode connected to a ground voltage, and a second electrode connected to the output terminal of the first inverter, and

the second inverter comprises:

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a second pull-up transistor having a gate connected to the output terminal of the first inverter, a first electrode connected to a power voltage, and a second electrode connected to an output terminal of the second inverter;

a second pull-down transistor having a gate connected to the output terminal of the first inverter, a first electrode, and a second electrode connected to the output terminal of the second inverter;

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a first transistor having a gate connected to the first electrode of the first pull-up transistor of the first inverter, a first electrode connected to the ground voltage, and a

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second electrode connected to the first electrode of the second pull-down transistor; and

a capacitor connected between the output terminal of the second inverter and the ground voltage.

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- 4. The sense amplifier driver of claim 3, further comprising at least one of a plurality of second transistors connected between the first electrode of the second pull-down transistor and the second electrode of the first transistor, each transistor of the plurality of second transistors having a gate connected to the first electrode of the first inverter.
- 5. The sense amplifier driver of claim 4, wherein a sense amplifier enable signal for enabling a sense amplifier is output from the output terminal of the second inverter.

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6. A sense amplifier driver comprising N (natural number) inverters connected in a series, wherein an n -1th (n a natural number greater than 2) inverter among the N inverters comprises:

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a first pull-up transistor having a gate for receiving an input signal, a first electrode for receiving a control voltage determined by the amount of an off-current flowing through a plurality of transistors, and a second electrode connected to an output terminal of the n-1th inverter; and

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a first pull-down transistor having a gate for receiving the input signal, a first electrode connected to a ground voltage, and a second electrode connected to the output terminal of the n-1th inverter, and

an nth inverter among the N inverters comprises:

a second pull-up transistor having a gate connected to the output terminal of the n-1th inverter, a first electrode connected to a power voltage, and a second electrode connected to an output terminal of the nth inverter;

a second pull-down transistor having a gate connected to the output terminal of the n-1th inverter, a first electrode, and a second electrode connected to the output terminal of the nth inverter;

a first transistor having a gate connected to the first electrode of the first pull-up transistor, a first electrode connected to the ground voltage, and a second electrode connected to the first electrode of the second pull-down transistor; and

a capacitor connected between the output terminal of the nth inverter and the ground voltage.

- 7. The sense amplifier driver of claim 6, wherein an n-2th inverter among the N inverters inverts a clock signal to generate the input signal, and an n+1th inverter among the N inverters is connected to the output terminal of the nth inverter.
- 8. The sense amplifier driver of claim 6, further comprising at least one of a plurality of second transistors connected between the first electrode of the second pull-down transistor and the second electrode of the first transistor, each transistor of the plurality of second transistors having a gate connected to the first electrode of the n -1th inverter.

A memory device comprising:

a memory cell array including a plurality of memory cells;

a delay control signal generation circuit which generates a delay control signal with a voltage determined by the amount of an off-current flowing through at least one transistor;

a sense amplifier driver which receives a clock signal, controls a period of time for which the clock signal is buffered according to the voltage of the delay control signal, and outputs a sense amplifier enable signal; and

a sense amplifier which senses and amplifies data of the memory cell array in response to the sense amplifier enable signal.

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10. The memory device of claim 9, wherein the sense amplifier driver includes:

a first inverter which receives the clock signal, and outputs an output signal swung between the voltage determined by the amount of an off-current and a ground voltage; and

a second inverter which receives the output signal of the first inverter, and delays and buffers the output signal of the first inverter by a period of time inversely proportional to a level of the voltage determined by the amount of an off-current.

- 11. The memory device of claim 9, wherein the period of time for which the clock signal is delayed is inversely proportional to the voltage of the delay control signal.
- 12. The memory device of claim 9, wherein the sense amplifier driver includes:

a first inverter which converts the clock signal into a signal swung between the voltage inversely proportional to the amount of an off-current and a ground voltage, and outputs the converted signal; and

a second inverter which is connected to the first inverter, controls a period of time for which the output signal of the first inverter is buffered in response to the voltage inversely proportional to the amount of an off-current, and outputs the sense amplifier enable signal,

wherein the period of time for which the output signal of the first inverter is buffered is proportional to the amount of off-current.

13. A memory device comprising:

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a memory cell array including a plurality of memory cells;

a delay control signal generation circuit including a dummy bit line and a complementary dummy bit line which are precharged to a predetermined voltage, a plurality of word lines respectively connected to ground voltages, and a plurality of transistors, each transistor having a gate connected to a corresponding word line of the word lines and a first electrode connected to the dummy bit line, a voltage of the dummy

bit line being determined according to a voltage drop due to an off-current flowing through the plurality of transistors;

a sense amplifier driver which receives a clock signal, controls a period of time for which the clock signal is buffered according to the voltage of the dummy bit line, and outputs a sense amplifier enable signal; and

a sense amplifier which senses and amplifies data of the memory cell array in response to the sense amplifier enable signal.

- 14. The memory device of claim 13, wherein the period of time for which the clock signal is buffered is inversely proportional to the voltage of the dummy bit line.
- 15. The memory device of claim 13, wherein the sense amplifier driver includes:

a first inverter which receives the clock signal, and outputs an output signal swung between the voltage of the dummy bit line and a ground voltage; and

a second inverter which receives the output signal of the first inverter, and delays and buffers the output signal of the first inverter by a period of time inversely proportional to a level of the voltage of the dummy bit line.

16. A memory device comprising:

a memory cell array including a plurality of memory cells;

a delay control signal generation circuit having a first electrode precharged to a power voltage, and a gate and a second electrode commonly connected to a ground voltage;

a sense amplifier driver which receives a clock signal, controls a period of time for which the clock signal is buffered according to a voltage of the first electrode, and outputs a sense amplifier enable signal; and

a sense amplifier which senses and amplifies data of the memory cell array in response to the sense amplifier enable signal.

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17. The memory device of claim 16, wherein the sense amplifier driver includes:

a first inverter which receives the clock signal, and outputs an output signal swung between the voltage of the first electrode and a ground voltage; and

a second inverter which receives the output signal of the first inverter, and delays and buffers the output signal of the first inverter by a period of time inversely proportional to a level of the voltage of the first electrode.

18. A method of outputting an enable signal for enabling a sense amplifier, comprising:

receiving an input signal and outputting an output signal swung between a ground voltage and a control voltage which is inversely proportional to the amount of an off-current flowing through at least one transistor in an inactive memory block; and

receiving the output signal, delaying and buffering the output signal by a period of time inversely proportional to a level of the control voltage, and outputting the enable signal.

- 19. The method of claim 18, wherein a point of time when the enable signal is activated is varied according to the level of the control voltage.
 - 20. A method of detecting data comprising:

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generating a delay control signal with a voltage determined by the amount of an off-current flowing through at least one transistor;

receiving a clock signal, controlling a period of time for which the clock signal is buffered according to the delay control signal, and outputting a sense amplifier enable signal; and

sensing and amplifying data of a memory cell array in response to the sense amplifier enable signal.

21. The method of claim 20, wherein the sense amplifier enable signal generation step includes:

receiving the clock signal and outputting an output signal swung between the voltage determined by the amount of an off-current and a ground voltage; and receiving the output signal, delaying and buffering the output signal by a period of time inversely proportional to a level of the voltage determined by the amount of an off-current, and outputting the sense amplifier enable signal.

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